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SHEET 1 OF 1

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				APPLICANT				
LIST OF REFERENCES CITED BY APPLICANT Stefan BECKER, et al.								
				FILING DATE		GROUP		
				August 2, 2006				
	·-			U.S. PATENT DOCUMENTS		<u> </u>		
EXAMINER		DOCUMENT	!	· · · · · · · · · · · · · · · · · · ·		SUB	FILING DATE	
INITIAL	İ	NUMBER	DATE	NAME	CLASS	CLASS	IF APPROPRIATE	
/HC/	AA	4 500 693	02-19-85	TAKEHARA, Hidetoshi et al.				
/HC/	AB	5 661 206	08-26-97	TANAKA, Yoshio et al.				
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		DOCUMENT NUMBER	DATE	COUNTRY	COUNTRY		TRANSLATION YES NO	
/HC/	AL	0 291 073	11-17-88	EP			NO	
/HC/	AM	58154761	09-14-83	JP (English abstract only and equivalen US 4946904)			NO	
/HC/	AN	58147413	09-02-83	JP (English abstract only)			NO	
/HC/ /HC/	AO		05-29-01	EP (equivalent of US 2004242760, US 2004235687 and US 2002099	115)		NO	
	AP	01 21542	03-29-01	WO (with English abstract)			NO	
/HC/	AQ	01 21541	03-29-01	WO (with English abstract)			NO	
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		OTHER REF	ERENCES (I	ncluding Author, Title, Date, Pertinent	Pages, e	tc.)		
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Examiner /Hui Chin/					Date Considered 01/14/2009			
Examiner: Init	ial if re	ference is considered, who considered. Include con-	hether or not	citation is in conformance with MPEP 60 with next communication to applicant.	9; Draw lii	ne through	citation if not in	
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